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Supplementary Materials for

Dirac nodal surfaces and nodal lines in ZrSiS

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Fig. S1. ARPES data collected with VUV lights.

Supplementary Materials

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Fig. S1. ARPES data collected with VUV lights. (A and B) FSs in the Γ -Z-R-X and Γ -Z-A-M planes, respectively, measured with varying photon energies from 30 to 100 eV. The orange lines indicate the boundary of Brillouin zones. (C to E) FSs measured with hv = 40, 46, and 52 eV, respectively.

To illuminate the k_z dispersions in the angle-resolved photoemission spectroscopy (ARPES) data with vacuum ultraviolet (VUV) lights, we have performed ARPES measurements along Γ -X and Γ -M directions in a range of photon energy (*hv*) from 30 to 100 eV. As seen in fig. S1 (A and B), the Fermi surfaces (FSs) measured in the VUV range exhibit straight lines along k_z , in sharp contrast to periodic warping in the soft X-ray data in Fig. 3 (C and D). As there are no periodic modulations along k_z in the VUV data, we calculate the k_z values with an inner potential of 23 eV, which is extracted from our soft X-ray data, and a lattice constant along *c* axis of 8.055 Å. We also measured the FSs with hv = 40, 46 and 52 eV, approximately corresponding to the $k_z = 0$, $\pi/2$, and π planes, respectively. As seen in fig. S1 (C to E), the measured FSs with VUV lights are almost the same, in sharp contrast to the remarkable changes in the soft X-ray data in Fig. 3 (G and H). The VUV ARPES results in fig. S1 show negligible k_z dispersions and are well reproduced by our slab calculations of the surface states in Fig. 1F, indicating that the VUV ARPES mainly detects the surface states of ZrSiS.